

RoHS Compliant Product
A Suffix of "-C" specifies halogen & lead-free

DESCRIPTIONS

The SMS3009E-C is N-Channel enhancement MOS Field Effect Transistor. Uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge.

This device is suitable for use in DC-DC conversion, load switch and level shift.

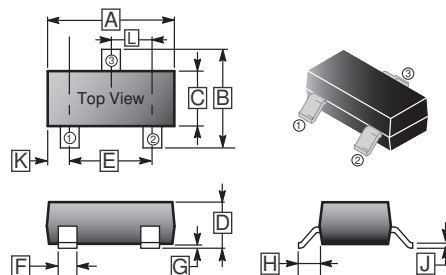
FEATURES

- Reliable and Rugged
- Green Device Available
- ESD Protection

MARKING

3009E

SOT-23



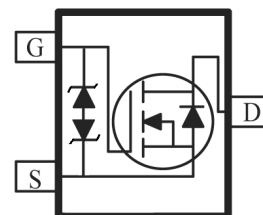
REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	2.70	3.10	G	0	0.18
B	2.10	3.00	H	0.55	REF.
C	1.20	1.80	J	0.08	0.26
D	0.89	1.3	K	0.6	REF.
E	1.70	2.3	L	0.95	BSC.
F	0.30	0.50			

PACKAGE INFORMATION

Package	MPQ	Leader Size
SOT-23	3K	7 inch

ORDER INFORMATION

Part Number	Type
SMS3009E-C	Lead (Pb)-free and Halogen-free



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ¹ , $V_{GS}=4.5V$	I_D	$T_A=25^\circ C$	0.6
		$T_A=70^\circ C$	0.48
Pulsed Drain Current ³	I_{DM}	2.4	A
Power Dissipation	P_D	0.35	W
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55~150	$^\circ C$
Thermal Data			
Thermal Resistance Junction-Ambient ¹	$R_{\theta JA}$	357	$^\circ C/W$
Thermal Resistance Junction-Ambient ²		500	
Thermal Resistance Junction-Case ¹		$R_{\theta JC}$	

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$ unless otherwise specified)

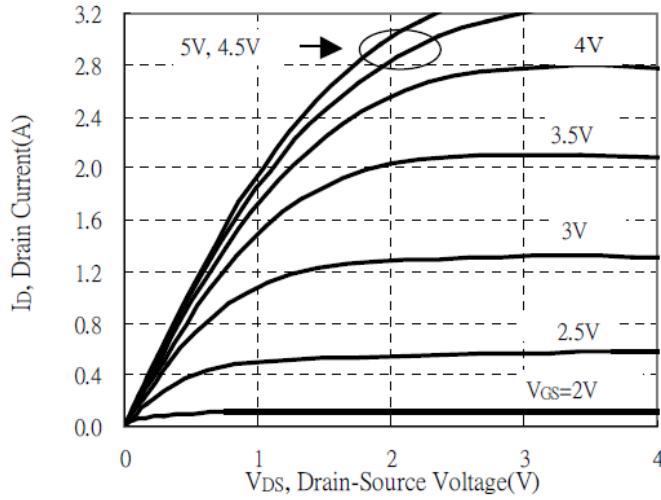
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions	
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$	
Gate Threshold Voltage	$V_{GS(TH)}$	0.6	-	1.3	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	
Gate-Source Leakage Current	I_{GSS}	-	-	± 10	μA	$V_{GS}=\pm 12\text{V}$	
Drain-Source Leakage Current	I_{DSS}	$T_J=25^\circ\text{C}$	-	-	1	μA	$V_{DS}=24\text{V}, V_{GS}=0$
		$T_J=55^\circ\text{C}$	-	-	25		$V_{DS}=24\text{V}, V_{GS}=0$
Static Drain-Source On-Resistance ⁴	$R_{DS(ON)}$	-	-	700	m Ω	$V_{GS}=4.5\text{V}, I_D=200\text{mA}$	
		-	-	1250		$V_{GS}=2.5\text{V}, I_D=100\text{mA}$	
		-	-	2000		$V_{GS}=1.8\text{V}, I_D=50\text{mA}$	
Total Gate Charge	Q_g	-	1.4	-	nC	$I_{DS}=0.6\text{A}$ $V_{DS}=15\text{V}$ $V_{GS}=4.5\text{V}$	
Gate-Source Charge	Q_{gs}	-	0.32	-			
Gate-Drain Charge	Q_{gd}	-	0.46	-			
Turn-on Delay Time	$T_{d(on)}$	-	8.6	-	nS	$V_{DD}=15\text{V}$ $I_{DS}=0.25\text{A}$ $V_{GS}=4\text{V}$ $R_{GEN}=10\Omega$	
Rise Time	T_r	-	17.4	-			
Turn-off Delay Time	$T_{d(off)}$	-	16.4	-			
Fall Time	T_f	-	16.4	-			
Input Capacitance	C_{iss}	-	41.93	-	pF	$V_{GS}=0$ $V_{DS}=15\text{V}$ $f=1\text{MHz}$	
Output Capacitance	C_{oss}	-	7.37	-			
Reverse Transfer Capacitance	C_{rss}	-	5.33	-			
Source-Drain Diode							
Continuous Source Current ¹	I_S	-	-	0.6	A		
Pulsed Source Current ³	I_{SM}	-	-	2.4	A		
Diode Forward Voltage ⁴	V_{SD}	-	0.85	1.2	V	$V_{GS}=0, I_S=0.3\text{A}, T_J=25^\circ\text{C}$	
Reverse Recovery Time	t_{rr}	-	6.7	-	nS	$I_F=0.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$ $T_J=25^\circ\text{C}$	
Reverse Recovery Charge	Q_{rr}	-	2.1	-	nC		

Notes:

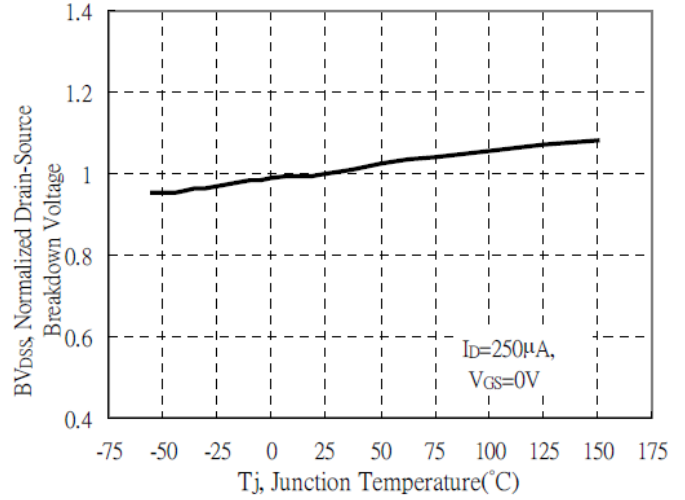
1. Surface mounted on a 1 inch² FR-4 board with 20Z copper.
2. Surface mounted on FR4 Board using the minimum recommended pad size.
3. Pulse width limited by maximum junction temperature, Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 1\%$.
4. The data tested by pulsed, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

CHARACTERISTIC CURVES

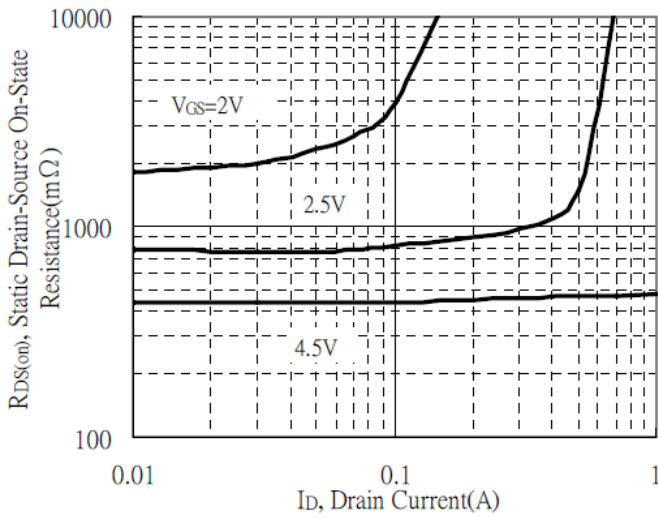
Typical Output Characteristics



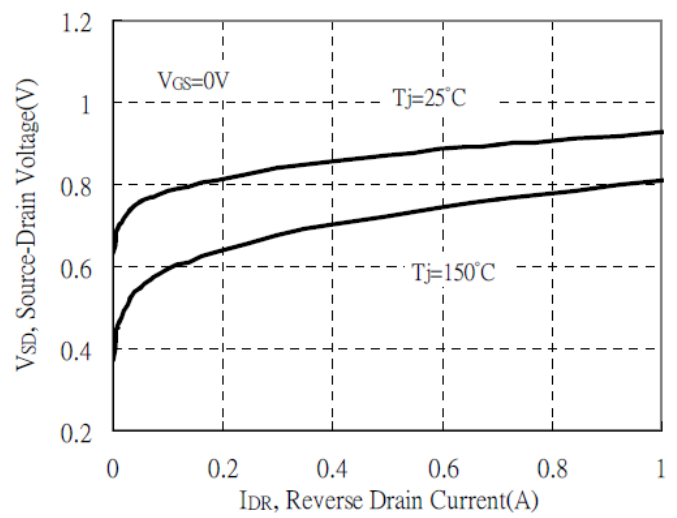
Breakdown Voltage vs Ambient Temperature



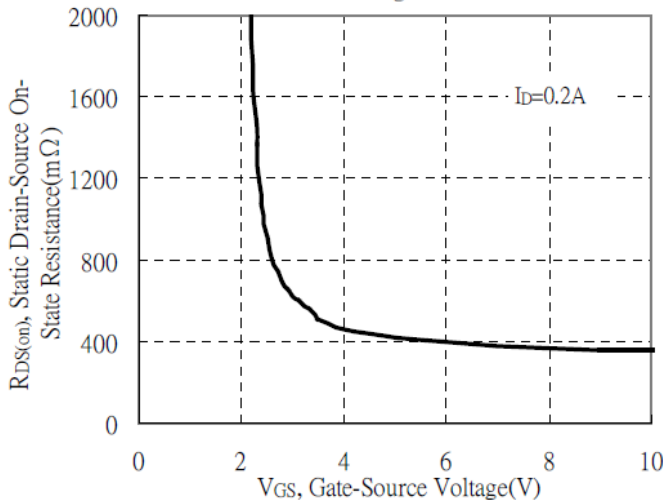
Static Drain-Source On-State resistance vs Drain Current



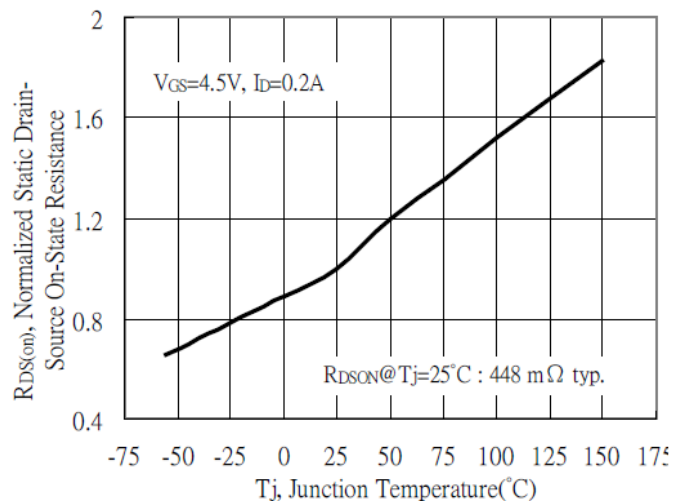
Reverse Drain Current vs Source-Drain Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage

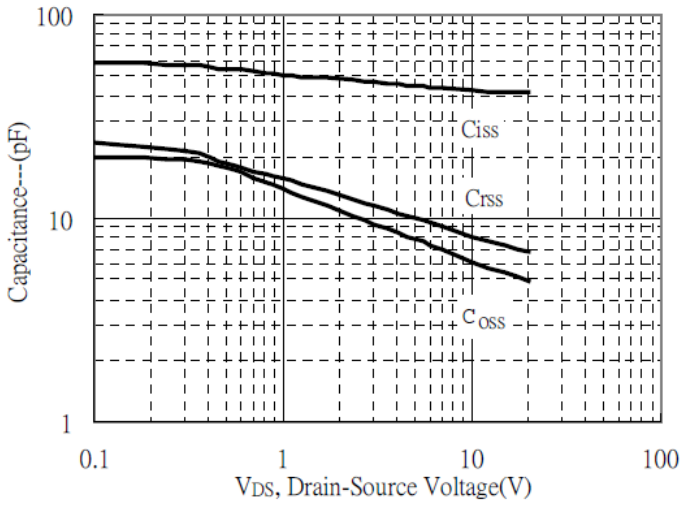


Drain-Source On-State Resistance vs Junction Temperature

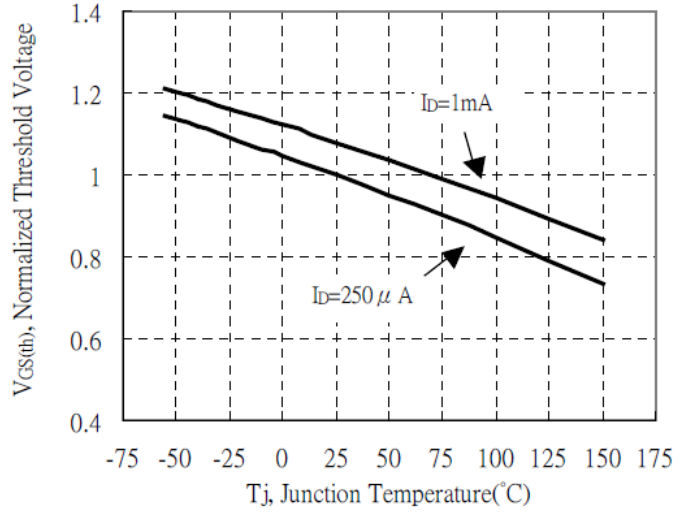


CHARACTERISTIC CURVES

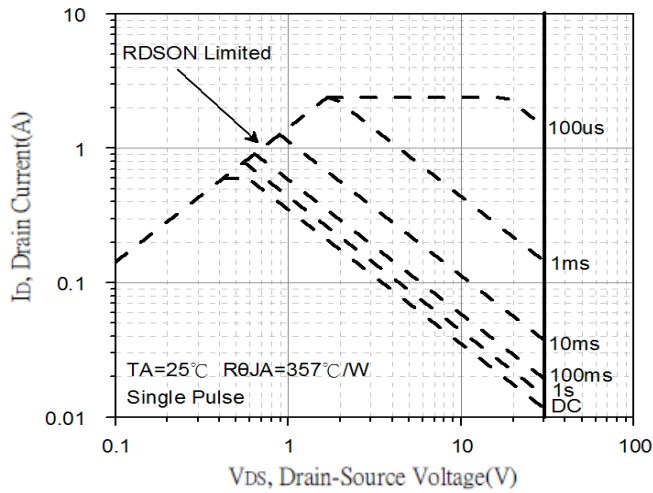
Capacitance vs Drain-to-Source Voltage



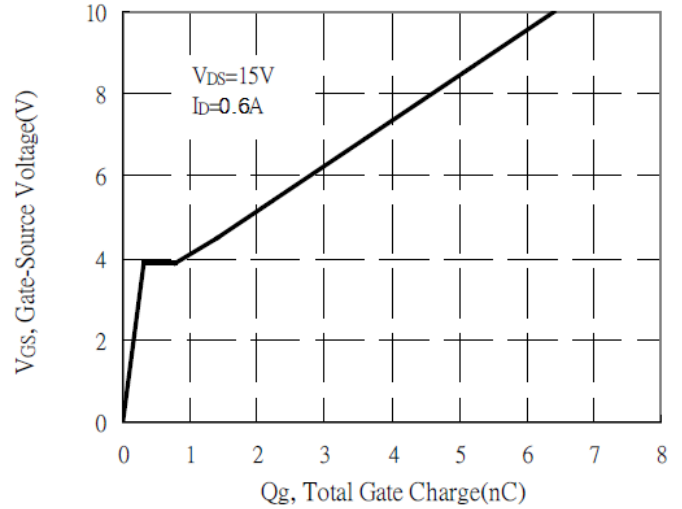
Threshold Voltage vs Junction Temperature



Maximum Safe Operating Area



Gate Charge Characteristics



Transient Thermal Response Curves

